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Texas Instruments SN54HC273VTDG1

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Distributor of Texas Instruments: Excellent Integrated System Limited

Datasheet of SN54HC273VTDG1 - IC GATE AND 4CH 2-INP DIE

Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com



SN54HC273-DIE

www.ti.com SCLS735 – JUNE 2013

RAD-TOLERANT SPACE GRADE DIE, QUADRUPLE 2-INPUT POSITIVE-AND GATES

Check for Samples: SN54HC273-DIE

FEATURES

- Wide Operating Voltage Range
- Outputs Can Drive Up To 10 LSTTL Loads
- Low Power Consumption
- Typical t_{pd} = 12 ns
- Low Input Current
- Contain Eight Flip-Flops With Single-Rail Outputs
- Direct Clear Input
- Applications Include:
 - Buffer/Storage Registers
 - Shift Registers
 - Pattern Generators

DESCRIPTION

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not related directly to the transition time of the positive-going pulse. When CLK is at either the high or low level, the D input has no effect at the output.

Table 1. FUNCTION TABLE (each flip-flop)

	OUPUT			
CLR	CLK	D	Q	
L	Х	Х	L	
Н	1	Н	Н	
Н	1	L	L	
Н	L	Х	Q_0	

ORDERING INFORMATION(1)

PRODUCT	PACKAGE DESIGNATOR	PACKAGE	ORDERABLE PART NUMBER	PACKAGE QUANTITY	
SN54HC273V	TD	Dare die in wettle neek(2)	SN54HC273VTDG1	100	
		Bare die in waffle pack ⁽²⁾	SN54HC273VTDG2	10	

⁽¹⁾ For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

⁽²⁾ Processing is per the Texas Instruments space production baseline and is in compliance with the Texas Instruments Quality Control System in effect at the time of manufacture. Electrical screening consists of DC parametric and functional testing at room temperature only. Unless otherwise specified by Texas Instruments AC performance and performance over temperature is not warranted. Visual Inspection is performed in accordance with MIL-STD-883 Test Method 2010 Condition B at 75X minimum.



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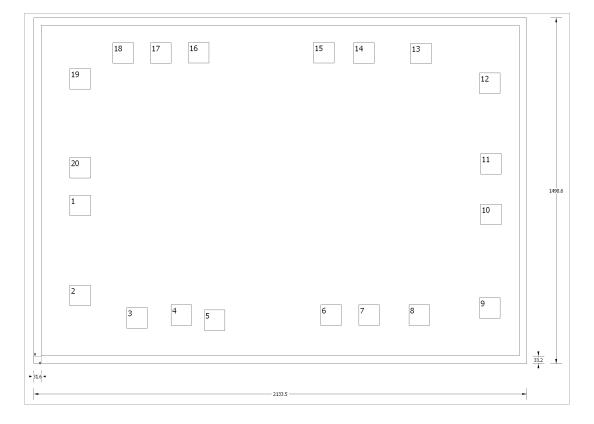


This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

BARE DIE INFORMATION

DIE THICKNESS	BACKSIDE FINISH	BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION	BOND PAD THICKNESS	
10.5 mils.	Silicon with backgrind	Floating	TiW/AlCu2%	1210 nm	



Product Folder Links: SN54HC273-DIE

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Table 2. Bond Pad Coordinates in Microns

DESCRIPTION	PAD NUMBER	X MIN	Y MIN	X MAX	Y MAX
CLR	1	124.05	606.65	214.05	696.65
1Q	2	124.05	216.95	214.05	306.95
1D	3	369.75	119.75	459.75	209.75
2D	4	562.35	132.35	652.35	222.35
2Q	5	706.35	109.85	796.35	199.85
3Q	6	1210.35	132.35	1300.35	222.35
3D	7	1375.05	132.35	1465.05	222.35
4D	8	1591.95	132.35	1681.95	222.35
4Q	9	1897.05	162.95	1987.05	252.95
GND	10	1901.55	567.95	1991.55	657.95
CLK	11	1901.55	786.65	1991.55	876.65
5Q	12	1897.05	1135.85	1987.05	1225.85
5D	13	1599.15	1264.55	1689.15	1354.55
6D	14	1351.65	1267.25	1441.65	1357.25
6Q	15	1178.85	1268.15	1268.85	1358.15
7Q	16	637.05	1268.15	727.05	1358.15
7D	17	473.25	1267.25	563.25	1357.25
8D	18	310.35	1267.25	400.35	1357.25
8Q	19	124.05	1154.75	214.05	1244.75
VCC	20	124.05	769.55	214.05	859.55



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PACKAGE OPTION ADDENDUM

6-Jun-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
SN54HC273VTDG1	ACTIVE			0	100	TBD	Call TI	N / A for Pkg Type			Samples
SN54HC273VTDG2	ACTIVE			0	10	TBD	Call TI	N / A for Pkg Type			Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design. PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability

information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that

lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight

in homogeneous material)

(9) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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